

Notice of References Cited	Application/Control No. 10/532,027	Applicant(s)/Patent Under Reexamination KATOH ET AL.	
	Examiner Camie S. Thompson	Art Unit 1774	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,326,868	07-1994	Thurkauf et al.	544/250
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP06-001972	01-1994	Japan	Ohishi et al	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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